

PCN Number:	20130507001			PCN Date:	05/09/2013
Title:	Qualification of JCAP as Alternate Assembly and test Site for selected products in DSBGA package				
Customer Contact:	PCN Manager	Phone:	+1(214)480-6037	Dept:	Quality Services
Proposed 1st Ship Date:	08/09/2013	Estimated Sample Availability:	05/09/2013		
Change Type:					
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification
<input checked="" type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process
<input checked="" type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process
PCN Details					
Description of Change:					
Qualification of JCAP as an alternate backend assembly and test site.					
Solder Ball:		TI Melaka-AT SnAgCu		JCAP-AT SnAgCu	
Reason for Change:					
Continuity of Supply					
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):					
None					
Changes to product identification resulting from this PCN:					
Assembly Site					
TIEM-AT	Assembly Site Origin (22L)			ASO: CU6	
JCAP-AT	Assembly Site Origin (22L)			ASO: JCP	
Sample product shipping label to show code location only - not actual product label					
Product Affected:					
LM10524TME/NOPB	LM3630TME/NOPB	LM3642TLX-LT/NOPB	LP5907UVX-2.8/NOPB		
LM10524TMX/NOPB	LM3630TMX/NOPB	LM3642TLX/NOPB	LP5907UVX-3.1/NOPB		
LM3630ATME	LM3642TLE-LT/NOPB	LP5907UVX-1.2/NOPB	LP5907UVX-4.5/NOPB		
LM3630ATMX	LM3642TLE/NOPB	LP5907UVX-1.8/NOPB			

Qualification Plan

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.						
Qual Vehicle: LM3564A1TME/NOPB (MSL1-260C)						
Qualification Schedule:	Start:	April 2013	End:	July 2013		
Package Construction Details						
Assembly & Bump Site:	JCAP	Bump Composition:	SnAgCu			
# Pins-Designator, Family:	20-YFQ, DSBGA	Bump Diameter:	0.25mm			
Qualification:	<input checked="" type="checkbox"/> Plan <input type="checkbox"/> Test Results					
Reliability Test	Conditions			Sample Size/Fail		
High Temp. Operating Life	125C (1000hrs)			77/0	77/0	77/0
Electrical Characterization	Per Datasheet specifications			30/0	--	--
High Temp. Storage Bake	150C (1000 Hrs)			77/0	--	--
**Biased HAST	130C/85%RH (96 Hrs)			77/0	77/0	77/0
**T/C -55C/125C	-55C/+125C (700 Cyc)			77/0	77/0	77/0
ESD CDM	+/- 250			3/0	3/0	3/0
ESD HBM	+/- 1000V			3/0	3/0	3/0
Latch-up (25C, 70C, 125C)	> 2 x Vddnom and >2 x Iddnom @ max Tj			6/0	6/0	6/0
Notes: **Tests require preconditioning sequence: MSL1-260C						

Qualification Results

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.						
Qualification Schedule:	Start:	January 2012	End:	April 2012		
Qualification Device: LP5907UVE (MSL 1-260C)						
Package Construction Details						
Assembly & Bump Site:	JCAP	Bump Composition:	SnAgCu			
# Pins-Designator, Family:	4 - YKE, DSBGA	Bump Diameter:	0.20mm			
Qualification:	<input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results					
Reliability Test	Conditions			Sample Size / Fail		
				Lot 1	Lot 2	Lot 3
High Temp. Operating Life	125C (1000hrs)			77/0	--	--
**Autoclave 121C	121C, 1 atm (96 Hrs)			77/0	80/0	80/0
**THBT	85C/85%			77/0	77/0	78/0
**T/C -40C/125C	-40C/+125C (1000 Cyc)			76/0	80/0	80/0
ESDH	2000V, 1.5K Ohm, 100pF			3/0	--	--
ESDM	200V, 0 Ohm, 200pF			3/0	--	--
Latch-up	I & OV test @ Max Op. Temp			6/0	--	--
Notes: **Tests require preconditioning sequence: MSL1-260C						

Qualification Results

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.			
Qualification Schedule:	Start:	January 2012	End: April 2012
Qualification Device: BP64UKE (MSL 1-260C)			
Package Construction Details			
Assembly & Bump Site:	JCAP	Bump Composition:	SnAgCu
# Pins-Designator, Family:	4 - YKE, DSBGA	Bump Diameter:	0.20mm
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results			
Reliability Test	Conditions	Sample Size / Fail	
Board Level Drop	--	pass	
Board Level TMCL	--	pass	

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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